

**Notice of References Cited**

Application/Control No.

10/080,844

Applicant(s)/Patent Under  
Reexamination  
LIN ET AL.

Examiner

Han Lieh Liu

Art Unit

3746

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5311090	05-1994	Ferlatte	310/88
	B	US-4521997	06-1985	Tiberend	52/3
	C	US-4631006	12-1986	Murray	417/234
	D	US-6093990	07-0200	Meeks et al.	310/91
	E	US-6592336 B1	07-2003	Hirano et al.	417/201
	F	US-6322326 B1	11-2001	Davis et al.	417/40
	G	US-5378119	01-1995	Goertzen	417/313
	H	US-5209653	05-1993	Murray et al.	417/410R
	I	US-5298824	03-1994	Franz	310/89
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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